**Product data sheet** 

## 1. General description

Planar passivated Silicon Controlled Rectifier (SCR) in a TO220F "full pack" plastic package intended for use in applications requiring good bidirectional blocking voltage and high current surge capability with high thermal cycling performance and high junction temperature capability ( $T_{j(max)} = 150 \, ^{\circ}$ C).

### 2. Features and benefits

- High junction operating temperature capability (T<sub>i(max)</sub> = 150 °C)
- Good bidirectional blocking voltage capability
- High current surge capability
- · High thermal cycling performance
- · Isolated mounting base package
- · Planar passivated for voltage ruggedness and reliability

## 3. Applications

- · Capacitive Discharge Ignition (CDI)
- Crowbar protection
- Inrush protection
- Motor control
- Voltage regulation
- High junction operating temperature capability (T<sub>j(max)</sub> = 150 °C)

### 4. Quick reference data

### Table 1 Quick reference data

Symbol	Parameter	Conditions	Values	Unit
Absolute r	naximum rating			
$V_{RRM}$	repetitive peak reverse voltage		650	V
$I_{T(RMS)}$	RMS on-state current	half sine wave; T <sub>h</sub> ≤ 94 °C; Fig. 1; Fig. 2; Fig. 3	12	А
I <sub>TSM</sub>	non-repetitive peak on- state current	half sine wave; $T_{j(init)} = 25$ °C; $t_p = 10$ ms; Fig. 4; Fig. 5	120	А
		half sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 8.3 \text{ ms}$	132	А
T <sub>j</sub>	junction temperature		150	°C

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static cha	Static characteristics						
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 7$		-	-	5	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>		-	7	20	mA
V <sub>T</sub>	on-state voltage	I <sub>τ</sub> = 12 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>		-	1.18	1.54	V
Dynamic o	Dynamic characteristics						
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 436 V; $T_j$ = 150 °C; $R_{GK}$ = 100 $\Omega$ ; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform;		200	1000	-	V/µs

# 5. Pinning information

**Table 2. Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode	mb	. N. v
2	А	anode		A 🕽 K G
3	G	gate		sym037
mb	n.c.	mounting base; isolated		

# 6. Ordering information

**Table 3. Ordering information** 

Type number	Package name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
BT151X-650LT	TO220F	BT151X-650LTQ	Tube	50	SOT186A	14-Nov-2013

# 7. Marking

### Table 4. Marking codes

Type number	Marking codes			
	Assembly factory: d	Assembly factory: A		
BT151X-650LT	BT151X 650LT PJdxxxx xx	BT151X 650LT PJAxxxx xx		

# 8. Limiting values

### **Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Values	Unit
$V_{DRM}$	repetitive peak off-state voltage		650	V
$V_{RRM}$	repetitive peak reverse voltage		650	V
I <sub>T(AV)</sub>	average on-state current	half sine wave; T <sub>h</sub> ≤ 94 °C	7.5	А
$I_{T(RMS)}$	RMS on-state current	half sine wave; T <sub>h</sub> ≤ 94 °C; Fig. 1; Fig. 2; Fig. 3	12	А
I <sub>TSM</sub>	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 10 ms; Fig. 4; Fig. 5	120	А
		half sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 8.3 \text{ ms}$	132	А
l <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10ms; sine wave	72	A <sup>2</sup> s
dl <sub>⊤</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 10mA	50	A/µs
I <sub>GM</sub>	peak gate current		2	А
$V_{RGM}$	peak reverse gate voltage		5	V
$P_{GM}$	peak gate power		5	W
$P_{G(AV)}$	average gate power	over any 20 ms period	0.5	W
T <sub>stg</sub>	storage temperature		-40 to 150	°C
T <sub>j</sub>	junction temperature		150	°C

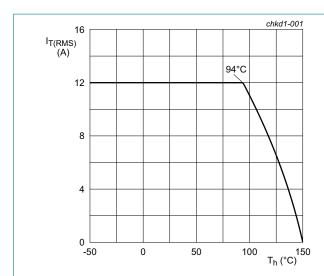
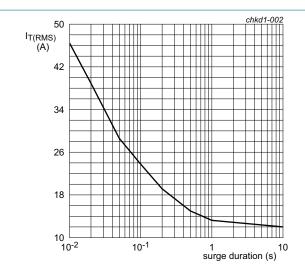


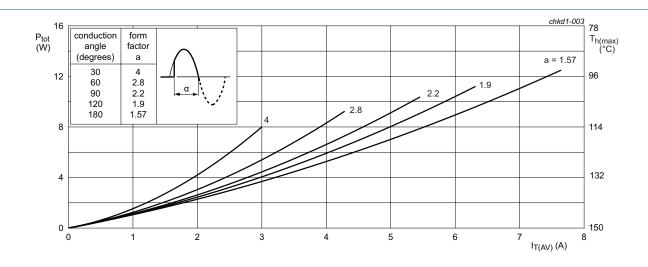
Fig. 1. RMS on-state current as a function of heatsink temperature; maximum values



 $f = 50 Hz; T_h = 94 °C$ 

Fig. 2. RMS on-state current as a function of surge duration; maximum values

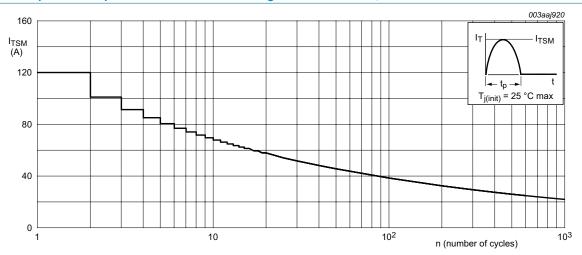
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 $\alpha$  = conduction angle

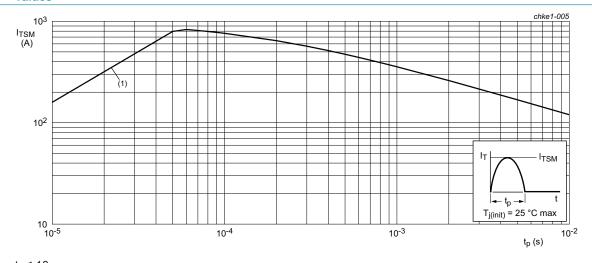
a = form factor =  $I_{T(RMS)} / I_{T(AV)}$ 

Fig. 3. Total power dissipation as a function of average on-state current; maximum values



f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



 $t_p \le 10 \text{ ms}$ ; (1)  $dI_T/dt \text{ limit}$ 

BT151X-650LT

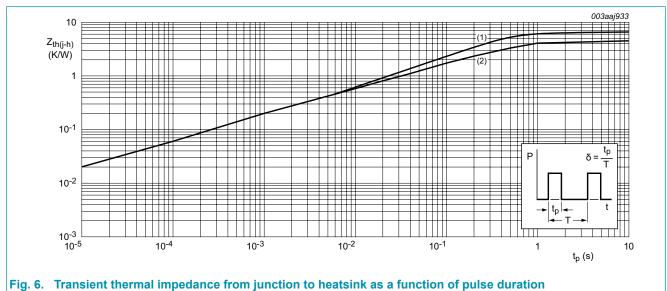
Fig. 5. Non-repetitive peak on-state current as a function of pulse width; maximum values

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## 9. Thermal characteristics

**Table 6. Thermal characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-h)</sub> thermal resistance		with heatsink compound; Fig. 6	-	-	4.5	K/W
	from junction to heatsink	without heatsink compound; Fig. 6	-	-	6.5	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient free air	in free air	-	55	-	K/W



## 10. Isolation characteristics

**Table 7. Isolation characteristics** 

Symb	ol Parameter	Conditions	Min	Тур	Max	Unit
V <sub>isol(RMS</sub>	RMS isolation voltage	50 Hz ≤ f ≤ 60 Hz; RH ≤ 65 %; from all pins to external heatsink; sinusoidal waveform; clean and dust free	-	-	2500	V
$C_{isol}$	isolation capacitance	from cathode to external heatsink	-	10	-	pF

## 11. Characteristics

Table 8 Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics	'				
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 ^{\circ}\text{C}; Fig. 7$	-	-	5	mA
I <sub>L</sub>	latching current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 ^{\circ}\text{C}; Fig. 8$	-	10	40	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	7	20	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 12 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.18	1.54	V
$V_{GT}$	gate trigger voltage	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T_j = 25 \text{ °C;}$ Fig. 11	-	0.6	1	V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 150 \text{ °C}$	0.2	0.4	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 650 V; T <sub>j</sub> = 150 °C	-	-	1	mA
I <sub>R</sub>	reverse current	V <sub>D</sub> = 650 V; T <sub>j</sub> = 150 °C	-	-	1	mA
Dynamic o	characteristics					
dV <sub>D</sub> /dt rate of rise of off-state voltage		$V_{DM}$ = 436 V; $T_j$ = 150 °C; $R_{GK}$ = 100 $\Omega$ ; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform;	200	1000	-	V/µs
		$V_{DM}$ = 436 V; $T_{j}$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	50	-	-	V/µs
<b>t</b> <sub>gt</sub>	gate-controlled turn-on time	$I_{TM} = 12 \text{ A}; V_D = 650 \text{ V}; I_G = 10 \text{ mA};$ $(dI_G/dt)_M = 5 \text{ A}/\mu\text{s}; T_j = 25 ^{\circ}\text{C}$		2	-	μs
t <sub>q</sub>	commutated turn-off time	$V_{DM} = 436 \text{ V; } T_j = 150 \text{ °C; } I_{TM} = 12 \text{ A; } $ $V_R = 25 \text{ V; } dV_D/dt = 30 \text{ V/}\mu\text{s; } (dI_T/dt)_M = 30 \text{ A/}\mu\text{s; } R_{GK(ext)} = 100 \Omega \text{ ; } (V_{DM} = 67\% \text{ of } V_{DRM})$		70	-	μs

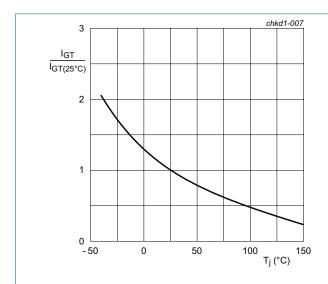


Fig. 7. Normalized gate trigger current as a function of junction temperature

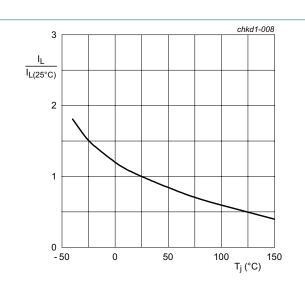


Fig. 8. Normalized latching current as a function of junction temperature

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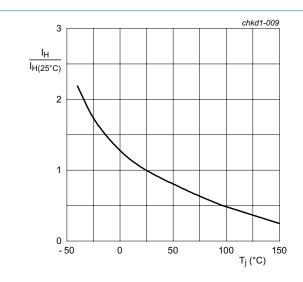
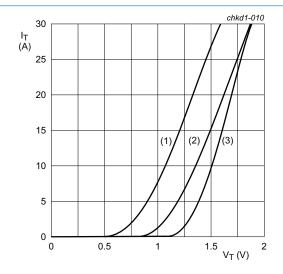


Fig. 9. Normalized holding current as a function of junction temperature



 $V_o$  = 0.967 V;  $R_s$  = 0.0354 Ω (1)  $T_j$  = 150 °C; typical values (2)  $T_j$  = 150 °C; maximum values (3)  $T_i$  = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

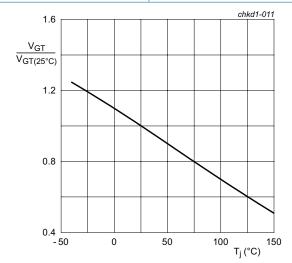
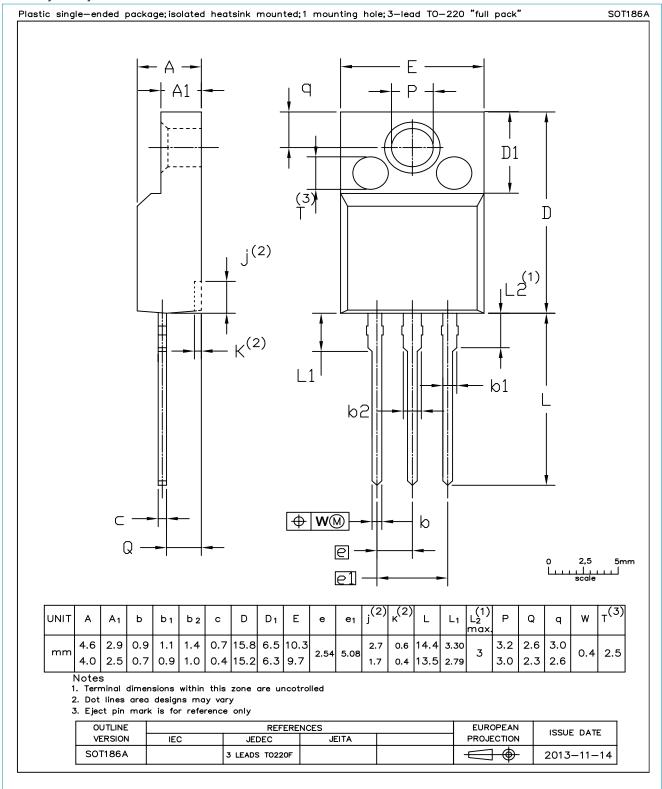


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

# 12. Package outline

Assembly factory: d & A



### 13. Legal information

### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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